

| | | | | |
|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/690,016 | | Applicant(s)/Patent Under Reexamination FENIZIA ET AL. | |
| | Examiner Brian P. Whipple | | Art Unit 2152 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-5,694,334 A | 12-1997 | Donahue et al. | 709/247 |
| * | B | US-2001/0016869 A1 | 08-2001 | Baumeister et al. | 709/203 |
| * | C | US-6,357,010 B1 | 03-2002 | Viets et al. | 726/4 |
| * | D | US-2002/0062357 A1 | 05-2002 | SRINIVASAN, THIRU | 709/219 |
| * | E | US-6,502,137 B1 | 12-2002 | Peterson et al. | 709/229 |
| * | F | US-7,065,341 B2 | 06-2006 | Kamiyama et al. | 455/411 |
| * | G | US-7,107,267 B2 | 09-2006 | Taylor, Julian S. | 707/8 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.